

<b>Notice of References Cited</b>	Application/Control No. 10/617,911	Applicant(s)/Patent Under Reexamination YIP ET AL.	
	Examiner Soon D. Hyun	Art Unit 2616	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,243,342	09-1993	Kattemalalavadi et al.	341/106
*	B	US-5,309,430	05-1994	Verhille et al.	370/397
*	C	US-5,353,283	10-1994	Tsuchiya, Paul F.	370/392
*	D	US-7,154,889	12-2006	Rekhter et al.	370/392
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.